



<p style="text-align: center;"><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10601015</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>AIK, ERIC TEH GIM</p>
	<p>Examiner</p> <p>Rossoshek, Helen</p>	<p>Art Unit</p> <p>2825</p>


Class	SubClass	Date	Examiner
716	3-5,10,11,14,17,18	08/01/2005	HR
714	725	08/01/2005	HR
702	117	08/01/2005	HR
UPDATED	UPDATED	04/24/2006	HR
UPDATED	UPDATED	09/08/2006	HR

U.S. Patent and Trademark Office	Part of Paper No.: 20060809
----------------------------------	-----------------------------

<b>Interference Searched</b>  	Application/Control No.  10601015	Applicant(s)/Patent Under Reexamination  AIK, ERIC TEH GIM
	Examiner Rossoshek, Helen	Art Unit 2825

Class	SubClass	Date	Examiner
716	4,18	08/09/2006	HR

U.S. Patent and Trademark Office	Part of Paper No.:	20060809
----------------------------------	--------------------	----------

<b>Search Notes</b>  	Application/Control No.  10601015	Applicant(s)/Patent Under Reexamination  AIK, ERIC TEH GIM
	Examiner Rossoshek, Helen	Art Unit 2825

Notes	Date	Examiner
EAST (USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB)	08/01/2005	HR
IEEE	08/01/2005	HR
PD	04/20/2006	HR
EAST (US-PGPUB). See search history printout	08/09/2006	HR
U.S. Patent and Trademark Office		Part of Paper No.: 20060809